

Notice of References Cited

Application/Control No.

10/587,241

Applicant(s)/Patent Under
Reexamination
SAITO ET AL.

Examiner

Vijay B. Chawan

Art Unit

2626

Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|----------------------|----------------|
| * | A | US-2007/0156408 | 07-2007 | Saito et al. | 704/260 |
| * | B | US-6,101,470 | 08-2000 | Eide et al. | 704/260 |
| * | C | US-7,487,093 | 02-2009 | Mutsuno et al. | 704/266 |
| * | D | US-6,199,042 | 03-2001 | Kurzweil, Raymond C. | 704/260 |
| * | E | US-4,912,768 | 03-1990 | Benbassat, Gerard V. | 704/260 |
| * | F | US-6,249,758 | 06-2001 | Mermelstein, Paul | 704/220 |
| * | G | US-7,249,021 | 07-2007 | Morio et al. | 704/258 |
| * | H | US-5,878,396 | 03-1999 | Henton, Caroline G. | 704/276 |
| * | I | US-6,151,576 | 11-2000 | Warnock et al. | 704/260 |
| * | J | US-7,039,588 | 05-2006 | Okutani et al. | 704/258 |
| * | K | US-6,826,531 | 11-2004 | Fukada, Toshiaki | 704/258 |
| * | L | US-2005/0149330 | 07-2005 | Katae, Nobuyuki | 704/267 |
| * | M | US-6,516,298 | 02-2003 | Kamai et al. | 704/260 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | | |
|---|---|-------------------------------------------------------------------------------------------|--|--|--|--|
| | U | | | | | |
| | V | | | | | |
| | W | | | | | |
| | X | | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 7.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.